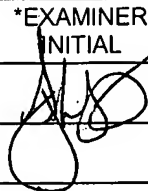



JC07 PCT/PTO 17 DEC 2001  
10/009979

FORM PTO-1449  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>LIST OF REFERENCES CITED BY APPLICANT</b>  (Use several sheets if necessary)	ATTORNEY DOCKET NO. <b>1454.1205</b>	APPLICATION NO.
	FIRST NAMED INVENTOR <b>Georg DENK</b>	
	FILING DATE	GROUP ART UNIT


**U.S. PATENT DOCUMENTS**

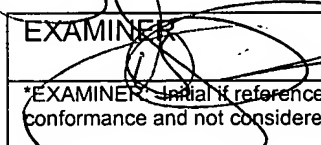
*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA	5,181,179	1/19/93	Fang et al.			
	AB						
	AC						
	AD						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO	
	AE	WO 98/24039	6/4/98	PCT				
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EXAMINER 	DATE CONSIDERED <b>26-SEPTEMBER-2003</b>
*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	